

Advanced Methods of Materials Characterization

Course Workload		Assessment form (examination/ graded test/ ungraded test)
ECTS	Hours	
6	216	Exam

Students will know physical phenomena underlying the methods of research and control of the composition, structure and properties of nanostructured materials; to be aware of the modern instrument base used for nanocharacterization, its main features and limitations; to describe the fundamental principles and principles of modern physical and chemical research methods..

Course structure:

1. Nanostructured materials and features of their characterization

- 1.1. Nanoscale objects and structures, their general classification and physicochemical features
- 1.2. The main methods for characterizing nanoscale objects: composition, dimension, specific surface area, shape (morphology), stability and functional response
- 1.3. Variety of modern methods and approaches of nanocharacterization (general overview and comparative analysis)
- 1.4. Review of modern devices used for nanomaterials characterization

2. Methods of transmission and scanning electron microscopy

- 2.1. The device and operation principle of an electron microscope
- 2.2. The main units of an electron microscope, their capabilities and limitations in the method resolution
- 2.3. Transmission and scanning (raster) electron microscopy
- 2.4. Possibilities of substances structural analysis by transmission microscopy
- 2.5. Capabilities of additional instrument modules and analysis tools
- 2.6. Detectors of secondary electrons, backscattered electrons, Auger electrons, characteristic X-rays and cathodoluminescence

3. Methods based on diffraction and scattering of X-ray, synchrotron and neutron radiation

- 3.1. X-ray diffraction of single crystals and polycrystalline materials
- 3.2. Transmission and reflective radiography techniques
- 3.3. Neutron diffraction
- 3.4. Possibilities of using synchrotron radiation
- 3.5. Primary X-ray processing and identification of substances
- 3.6. Wolfe-Bragg formula
- 3.7. Particles' or polycrystalline materials grains' size effect on the broadening of diffraction peaks
- 3.8. Scherrer's formula
- 3.9. Possibilities of small-angle diffraction and small-angle scattering in the study of thin films and nanostructured materials

4. Optical spectroscopy methods

- 4.1. Phenomena of light absorption and emission by substances
- 4.2. Excited states of atoms and molecules, principles of light absorption and emission spectroscopy near the visible range
- 4.3. Basic energy states of molecules: electronic, vibrational and rotational
- 4.4. Quantum levels, forced transitions and energy spectra
- 4.5. Jablonsky diagram. Stokes shift. Singlet and triplet states
- 4.6. Fluorescence. Phosphorescence. Spectrophotometry and fluorimetry
- 4.7. Review of the main laws governing the formation of absorption and emission spectra by various molecular groups and compounds
- 4.8. Quantitative analysis capabilities by spectrometry and spectrofluorimetry
- 4.9. Bouguer-Lambert-Beer law and its practical application. Possible nonlinear deviations

5. Vibrational spectroscopy methods

- 5.1. Vibrational spectra of diatomic and polyatomic molecules
- 5.2. Energy levels of electronic states, their classification
- 5.3. Intensity of vibrational spectra bands
- 5.4. Selection rules and intensity of IR radiation absorption
- 5.5. Raman spectroscopy
- 5.6. Stokes and anti-Stokes shifts

6. Investigation of disperse systems by the method of dynamic light scattering

- 6.1. Colloidal solutions and suspensions
- 6.2. Hydrodynamic radius of particles and its relationship with mobility in viscous solutions
- 6.3. Brownian motion. Stokes-Einstein ratio
- 6.4. Determination of the particle hydrodynamic radius by the analysis of dynamic light scattering
- 6.5. Using autocorrelation functions to calculate the hydrodynamic radius of particles

- 6.6. Estimation of the statistical particle size distribution. Influence of solution parameters on measurement accuracy
- 6.7. Overview of the possibilities and limitations of the method
- 6.8. Electric double layer on particle surfaces in finely dispersed systems
- 6.9. Stability of colloidal solutions
- 6.10. Zeta potential, main approaches to its definition
- 6.11. Comparative analysis of electrophoretic and electroacoustic methods for determining zeta potential

7. Methods for characterizing the porous structure and surface properties of materials

- 7.1. Low-temperature physical nitrogen sorption method
- 7.2. Materials with high porosity and high specific surface area
- 7.3. The phenomenon of surface gas adsorption and its use for quantitative characterization of the specific surface area and porosity of materials
- 7.4. Basic models of gas sorption-desorption under isothermal conditions. Monolayer formation
- 7.5. Capillary condensation processes in mesoporous structures
- 7.6. Langmuir isotherm. Isotherms of Temkin, Freundlich, BET model and others, peculiarities of their application in characterization by the adsorption method
- 7.7. Hysteresis of adsorption-desorption isotherms, its analysis for characterization of porous structures
- 7.8. Study of the hydrophilic-hydrophobic properties of the surface by analyzing the shape of a drop

8. Atomic force microscopy

- 8.1. Atomic force microscopy. Cantilever device, its mechanical characteristics
 - 8.2. Hooke's Law. The phenomenon of mechanical resonance, determination of the cantilever natural frequencies
 - 8.3. The main scanning modes and their capabilities: contact, non-contact, semi-contact
 - 8.4. Topographic scanning modes: "constant height" and "constant force"
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